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SanKen SANKEN ELECTRIC 2 S K 3 7 1 0

May. 2011

Features Package Low on-state resistance 5.0mΩ VGS=10V TO220S • Built-in gate protection diode ·SMD PKG **Applications** \cdot DC-DC converter • Mortar drive **Internal Equivalent Circuit** D(2) **Key Specifications** \cdot V(BR)DSS = 60V (ID=100uA) \cdot RDS(ON) = 5m Ω max (ID=35A / VGS=10V) G(1) S (3) Absolute maximum ratings (Ta=25°C) Characteristic Symbol Rating Unit 60 V V_{DSS} Drain to Source Voltage V_{GSS} V Gate to Source Voltage ± 20 Continuous Drain Current $I_{\rm D}$ ± 85 А I_{D(pulse)}^{*1} Pulsed Drain Current ± 170 А $100 (Tc=25^{\circ}C)$ W Maximum Power Dissipation $P_{\rm D}$ $E_{AS} \, {}^{\ast 2}$ Single Pulse Avalanche Energy 400 mJ Maximum avalanche current 25 А I_{AS} 150 °C **Channel Temperature** T_{ch} Storage Temperature T_{stg} $-55 \sim +150$ °C $dv/dt 1^{*2}$ Maximum Drain to Source dv/dt 1 0.5 V/ns $dv/dt 2^{*3}$ 3 V/ns Peak diode recovery dv/dt 2 di/dt*3 100 Peak diode recovery di/dt A/µs *1 PW \leq 100µsec. duty cycle \leq 1% *2 V_{DD} =20V, L=1mH, I_L=25A, unclamped, Rg=50 Ω , See Fig.1

*3 I_{SD} =25A, See Fig.2

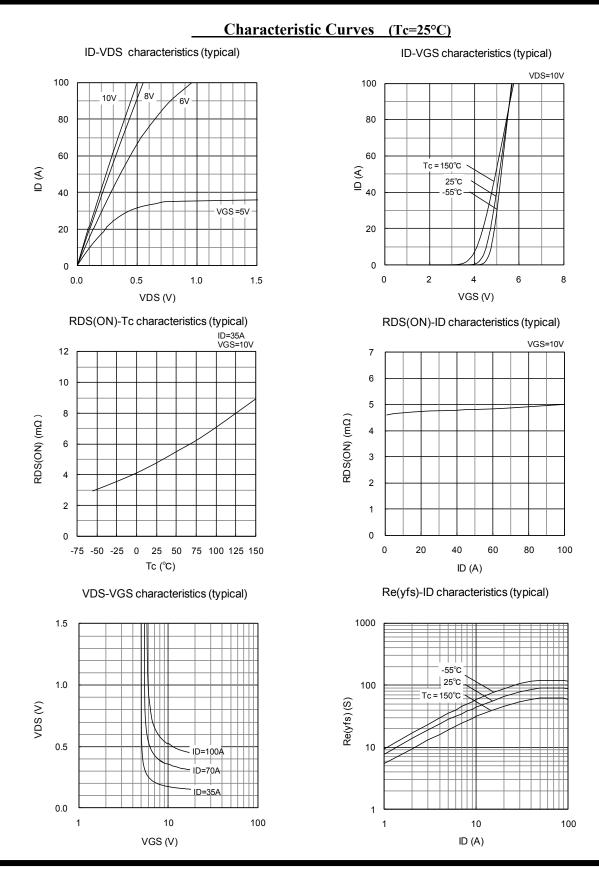
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	Electric	al characteristics			(Ta-25°C)	
Characteristic	Symbol	Test Conditions	(Ta=25°C) Limits			
			MIN	ТҮР	MAX	Unit
Drain to Source breakdown Voltage	V _{(BR)DSS}	I _D =100μA V _{GS} =0V	60			V
Gate to Source Leakage Current	I _{GSS}	V _{GS} =±15V			± 10	μΑ
Drain to Source Leakage Current	I _{DSS}	V _{DS} =60V V _{GS} =0V			100	μΑ
Gate Threshold Voltage	V_{TH}	$V_{DS}=10V$, $I_{D}=1mA$	2.0	3.4	4.0	V
Forward Transconductance	Re(yfs)	$V_{DS}=10V$ $I_{D}=35A$	30	80		S
Static Drain to Source On-Resistance	R _{DS(ON)}	I _D =35A, V _{GS} =10V		5.0	6.0	mΩ
Input Capacitance	Ciss	$V_{DS}=10V$ $V_{GS}=0V$ f=1MHz		8400		
Output Capacitance	Coss			1200		pF
Reverse Transfer Capacitance	Crss			930		
Turn-On Delay Time	td(on)	$I_{D}=35A$ $V_{DD}=20V$ $R_{G}=22\Omega$ $R_{GS}=50\Omega$ $R_{L}=0.57\Omega$ $V_{GS}=10V$ See Fig.3		160		ns
Rise Time	tr			170		
Turn-Off Delay Time	td(off)			430		
Fall Time	tſ			185		
Source-Drain Diode Forward Voltage	V _{SD}	I _{SD} =50A V _{GS} =0V		0.9	1.5	V
Source-Drain Diode Reverse Recovery Time	trr	I _{SD} =25A di/dt=50A/µs		65		ns
Thermal Resistance Junction to Case	Rth(ch-c)				1.25	°C/W
Thermal Resistance Junction to Ambient	Rth(ch-a)				62.5	°C/W

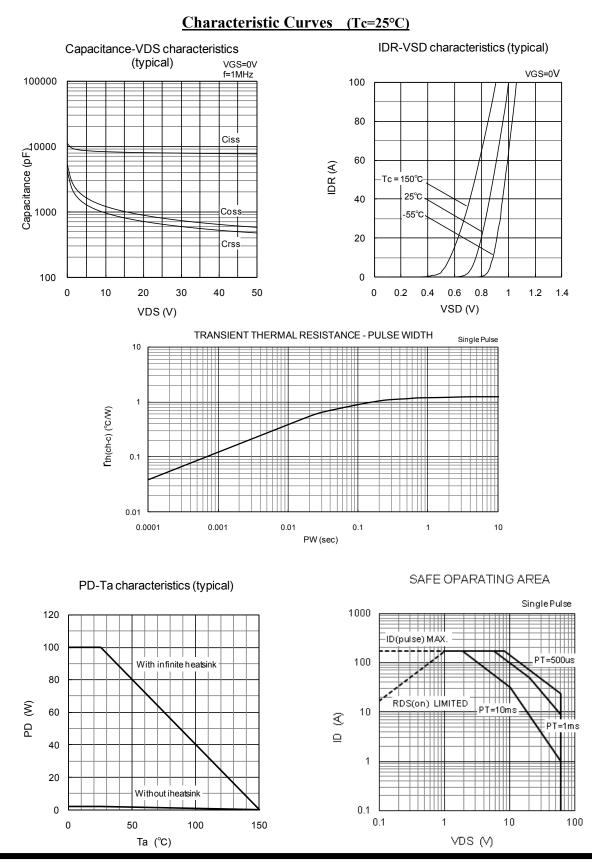
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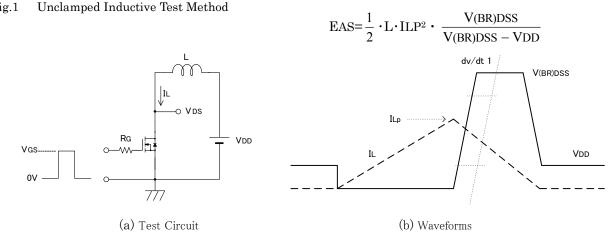
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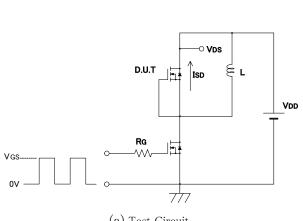
Fig.1 Unclamped Inductive Test Method

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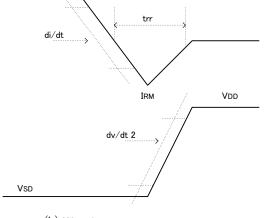


ISD

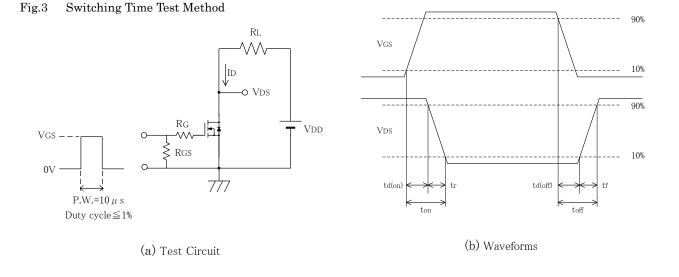




(a) Test Circuit





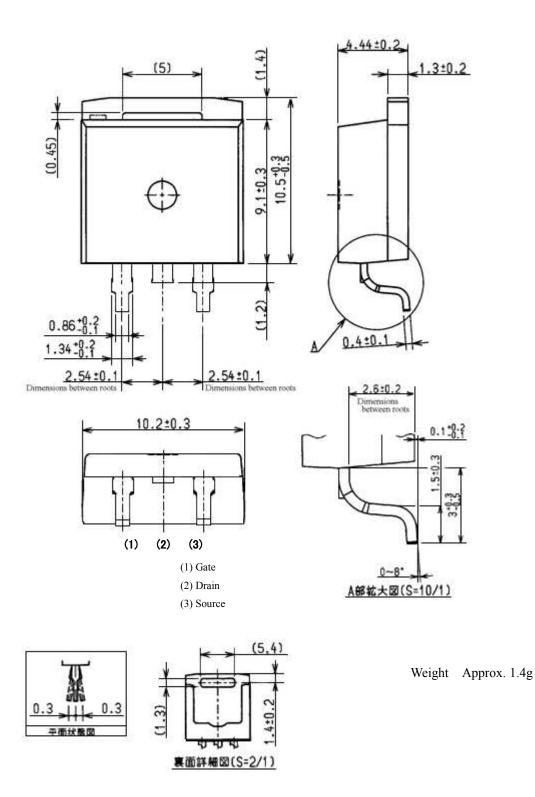


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TO220S



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